Notice of References Cited	Application/Control No. 10/078,876	Applicant(s)/Patent Under Reexamination HATHAWAY ET AL.	
	Examiner Joseph D. Torres	Art Unit 2133	Page 1 of 1

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	L	US-			
	M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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